# **Power MOSFET**

# 30 V, 52 A, Single N-Channel, μ8FL

#### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

## **Applications**

- DC-DC Converters
- Power Load Switch
- Notebook Battery Management

### MAXIMUM RATINGS (T<sub>.1</sub> = 25°C unless otherwise stated)

Param	Symbol	Value	Unit			
Drain-to-Source Voltage	$V_{DSS}$	30	V			
Gate-to-Source Voltage	$V_{GS}$	±20	V			
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	15	Α	
Current $R_{\theta JA}$ (Note 1)		T <sub>A</sub> = 85°C	1	10.8		
Power Dissipation $R_{\theta JA}$ (Note 1)			P <sub>D</sub>	2.13	W	
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	21	Α	
Current $R_{\theta JA} \le 10 \text{ s}$ (Note 1)		T <sub>A</sub> = 85°C		15		
Power Dissipation $R_{\theta JA} \le 10 \text{ s (Note 1)}$	Steady	T <sub>A</sub> = 25°C	P <sub>D</sub>	4.2	W	
Continuous Drain	State	T <sub>A</sub> = 25°C	I <sub>D</sub>	9.3	Α	
Current R <sub>θJA</sub> (Note 2)		T <sub>A</sub> = 85°C		6.7		
Power Dissipation $R_{\theta JA}$ (Note 2)		T <sub>A</sub> = 25°C	P <sub>D</sub>	0.82	W	
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	52	Α	
Current R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 85°C		37.5		
Power Dissipation $R_{\theta JC}$ (Note 1)		T <sub>C</sub> = 25°C	P <sub>D</sub>	25.5	W	
Pulsed Drain Current	T <sub>A</sub> = 25°0	C, t <sub>p</sub> = 10 μs	$I_{DM}$	144	Α	
Operating Junction and S	T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C			
Source Current (Body Die	IS	23	Α			
Drain to Source dV/dt	dV/dt	6.0	V/ns			
Single Pulse Drain-to-So $(T_J = 25^{\circ}C, V_{GS} = 10 \text{ V}, I_{G} = 25 \Omega)$ (Note 3)	E <sub>AS</sub>	42	mJ			
Lead Temperature for So (1/8" from case for 10 s)	T <sub>L</sub>	260	°C			

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size.
- 3. This is the absolute maximum ratings. Parts are 100% tested at  $T_J = 25$ °C,  $V_{GS} = 10 \text{ V}, I_L = 21 \text{ A}, E_{AS} = 22 \text{ mJ}.$

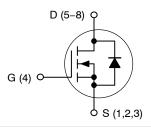


# ON Semiconductor®

### http://onsemi.com

V <sub>(BR)DSS</sub> R <sub>DS(on)</sub> MAX		I <sub>D</sub> MAX
30 V	5.9 mΩ @ 10 V	52 A
	9.0 mΩ @ 4.5 V	32 A

### **N-Channel MOSFET**





# (μ8FL) CASE 511AB



4C08 = Specific Device Code Α = Assembly Location

= Year WW = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

### ORDERING INFORMATION

Device	Package	Shipping <sup>†</sup>
NTTFS4C08NTAG	WDFN8 (Pb-Free)	1500 / Tape & Reel
NTTFS4C08NTWG	WDFN8 (Pb-Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

# THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	4.9	
Junction-to-Ambient - Steady State (Note 4)	$R_{\theta JA}$	58.8	°C/W
Junction-to-Ambient - Steady State (Note 5)	$R_{\theta JA}$	153	°C/VV
Junction-to-Ambient - (t ≤ 10 s) (Note 4)	$R_{\theta JA}$	30	

- Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
   Surface-mounted on FR4 board using the minimum recommended pad size.

# **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS				•	•		•
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage (transient)	V <sub>(BR)DSSt</sub>	$V_{GS} = 0 \text{ V, } I_{D(aval)} = 12.6 \text{ A,}$ $T_{case} = 25^{\circ}\text{C, } t_{transient} = 100 \text{ ns}$		34			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				13.8		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 24 V	T <sub>J</sub> = 25°C			1.0	
			T <sub>J</sub> = 125°C			10	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub>	= ±20 V			±100	nA
ON CHARACTERISTICS (Note 6)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D$	= 250 μΑ	1.3		2.2	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				5.0		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 30 A		4.7	5.9	mΩ
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 18 A		7.2	9.0	
Forward Transconductance	9FS	V <sub>DS</sub> = 1.5 V, I <sub>E</sub>	<sub>0</sub> = 15 A		42		S
Gate Resistance	$R_{G}$	T <sub>A</sub> = 25°C			1.0		Ω
CHARGES AND CAPACITANCES							-
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 15 V			1113		pF
Output Capacitance	C <sub>OSS</sub>				702		
Reverse Transfer Capacitance	C <sub>RSS</sub>				39		1
Capacitance Ratio	C <sub>RSS</sub> /C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 15	V, f = 1 MHz		0.035		
Total Gate Charge	Q <sub>G(TOT)</sub>				8.4		
Threshold Gate Charge	Q <sub>G(TH)</sub>				1.8		nC
Gate-to-Source Charge	$Q_{GS}$	$V_{GS} = 4.5 \text{ V}, V_{DS} = 1$	5 V; I <sub>D</sub> = 30 A		3.5		
Gate-to-Drain Charge	$Q_{GD}$				3.3		1
Gate Plateau Voltage	$V_{GP}$				3.4		V
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 15 V; I <sub>D</sub> = 30 A			18.2		nC
SWITCHING CHARACTERISTICS (Note 7)							
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS}$ = 4.5 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			9.0		ns
Rise Time	t <sub>r</sub>				33		
Turn-Off Delay Time	t <sub>d(OFF)</sub>				15		
Fall Time	t <sub>f</sub>				4.0		

- 6. Pulse Test: pulse width  $\leq$  300  $\mu\text{s},$  duty cycle  $\leq$  2%.
- 7. Switching characteristics are independent of operating junction temperatures.

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	ote 7)	•		•			
Turn-On Delay Time	t <sub>d(ON)</sub>				7.0		
Rise Time	t <sub>r</sub>	$V_{GS}$ = 10 V, $V_{DS}$ = 15 V, $I_D$ = 15 A, $R_G$ = 3.0 $\Omega$			26		- ns
Turn-Off Delay Time	t <sub>d(OFF)</sub>				19		
Fall Time	t <sub>f</sub>			3.0			
DRAIN-SOURCE DIODE CHARACTI	ERISTICS						
Forward Diode Voltage	$V_{SD}$	VGS - 0 V,	T <sub>J</sub> = 25°C		0.79	1.1	V
			T <sub>J</sub> = 125°C		0.66		
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, dIS/dt} = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 30 \text{ A}$			28.3		
Charge Time	t <sub>a</sub>				14.5		ns
Discharge Time	t <sub>b</sub>				13.8		
Reverse Recovery Charge	$Q_RR$				15.3		nC

<sup>6.</sup> Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%.
7. Switching characteristics are independent of operating junction temperatures.

### TYPICAL CHARACTERISTICS

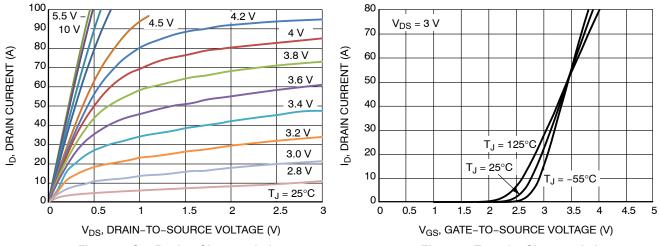


Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics

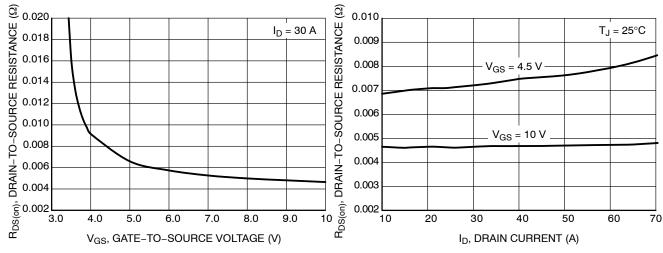


Figure 3. On-Resistance vs. V<sub>GS</sub>

Figure 4. On-Resistance vs. Drain Current and Gate Voltage

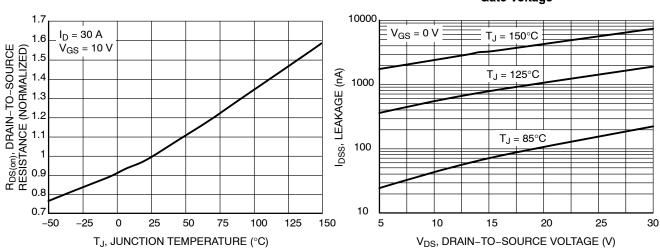


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

### TYPICAL CHARACTERISTICS

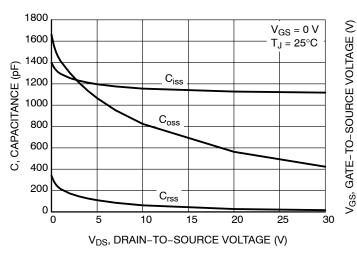


Figure 7. Capacitance Variation

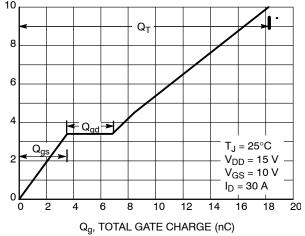


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

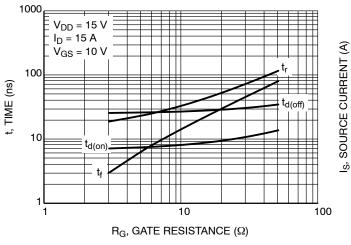


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

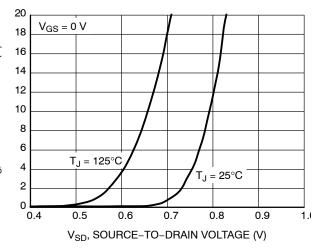


Figure 10. Diode Forward Voltage vs. Current

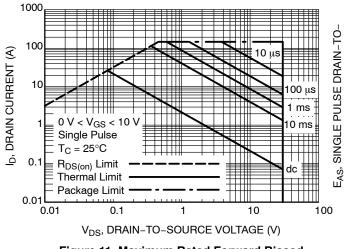


Figure 11. Maximum Rated Forward Biased Safe Operating Area

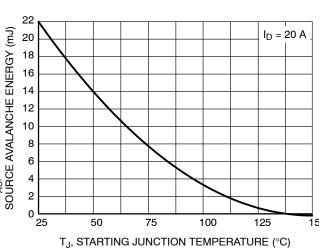


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

# **TYPICAL CHARACTERISTICS**

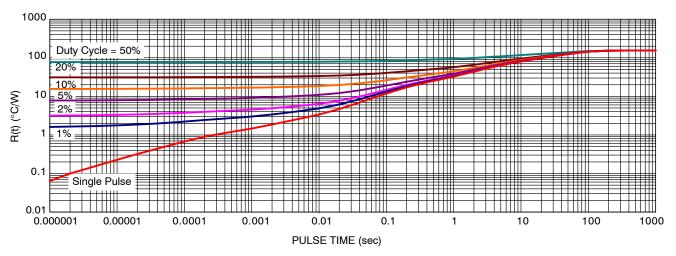


Figure 13. Thermal Response

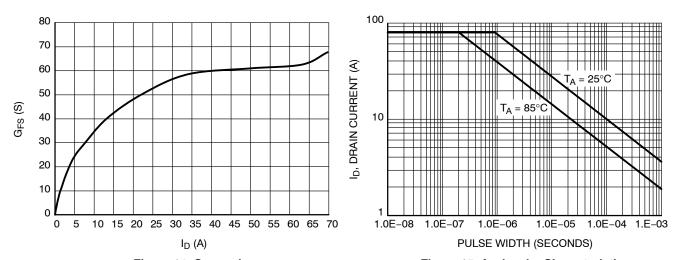
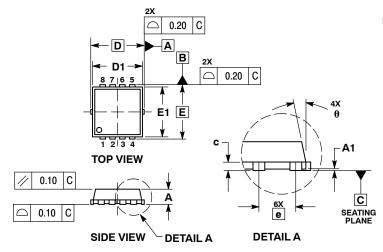


Figure 14. G<sub>FS</sub> vs. I<sub>D</sub> Figure 15. Avalanche Characteristics

### PACKAGE DIMENSIONS

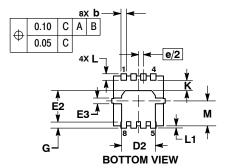
### WDFN8 3.3x3.3, 0.65P CASE 511AB ISSUE D



#### NOTES

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

	MILLIMETERS			INCHES			
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.70	0.75	0.80	0.028	0.030	0.031	
A1	0.00		0.05	0.000		0.002	
b	0.23	0.30	0.40	0.009	0.012	0.016	
C	0.15	0.20	0.25	0.006	0.008	0.010	
D		3.30 BSC		C	.130 BSC	;	
D1	2.95	3.05	3.15	0.116	0.120	0.124	
D2	1.98	2.11	2.24	0.078	0.083	0.088	
Е		3.30 BSC		0.130 BSC			
E1	2.95	3.05	3.15	0.116	0.120	0.124	
E2	1.47	1.60	1.73	0.058	0.063	0.068	
E3	0.23	0.30	0.40	0.009	0.012	0.016	
е		0.65 BSC	;	0.026 BSC			
G	0.30	0.41	0.51	0.012	0.016	0.020	
K	0.65	0.80	0.95	0.026	0.032	0.037	
L	0.30	0.43	0.56	0.012	0.017	0.022	
L1	0.06	0.13	0.20	0.002	0.005	0.008	
М	1.40	1.50	1.60	0.055	0.059	0.063	
θ	0 °		12 °	0 °		12 °	



# **SOLDERING FOOTPRINT\*** 8X 0.42 4X ⊢0.66 3.60 0.75 0.57 2.30 0.47 2.37 3.46

**DIMENSION: MILLIMETERS** 

\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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